

Calibration Strategy and Experimental Qualification of the First DEPFET Pixel Sensors of the DSSC Camera



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Detectors for EuXFEL: a challenging detection system

FEL: high brilliance X-ray source generating ultra-short X-ray pulses

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2 versions developed: miniSDD based, DEPFET based

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DSSC camera 1st version: 1MPxl miniSDD







World's fastest soft X-ray imager

- Available for experiments since 05/2019
- Pixel based on Silicon Drift Detectors
- Noise level ~60 electrons @ 4.5MHz
 FWHM ~ 500 eV



Büttner, F; et al. Observation of fluctuation-mediated picosecond nucleation of a topological phase. **Nat. Mater**. 20, 30–37 (2021). doi:10.1038/s41563-020-00807-1



- In-pixel **8-bit digitization** (9-bit @ f<4.5MHz)
- In-pixel SRAM (800 frames/burst) → limited ADC resolution

MiniSDD

Front-End

DEPFET

Front-End

EGE

test signals

229um

SRAM

Cntrl

ADC

local reference

- Data transmission during gaps
- 11 settings of Cfcf (coarse gain) for photon energy/dyn. range selection, 6 bits of ADC gain fine trimming
- 4 bits for offset trimming

BUT...

- Limited dynamic range (linear system)
- Limited SNR for the lowest energy range



DSSC camera 2nd version: DEPFET signal compression

Second camera under development is based on the same architecture as the first, but with another pixel sensor

DEPFET Sensor with Signal Compression

DEPFET

- → DEpleted P-channel Field Effect Transistor
- → FET on fully depleted silicon substrate -> active pixel
- \mapsto internal gate induces changes in the FET current -> signal

Compression

- → internal gate extends under the source and charges gradually spread farther from FET channel, leading to lower inductive effect per-electron
- \rightarrow non-linear $\Delta I/Q_{sig}$ curve



Camera module and ASICs



DEPFET pixel



- → accurate calibration of multiple DSSC properties is requested (gain, offset, QE, charge-sharing, etc)
- → particular importance to the qualification of the NL system response over the full dynamic range

calibration is a challenge by itself

The challenge of calibration

Two-step procedure:

- 1. Calibration of gain/offset in the linear region for all settings
 - a) Acquisition of hard X-ray spectra with single high gain setting
 - low resolution 8 bit ADC makes difficult the assessment of the gain from acquired spectra with adequate accuracy
 - b) In-ASIC charge injection circuit to probe all gain configurations and generate a LookUpTable of gain ratios
- 2. Qualification of the shape of non-linear (NL) DEPFET response by scanning the whole energy range up to few MeV/pixel
 - Few options: optical (LED/laser), leakage current, XFEL beam

high energy and uniformity on wide surface area needed, Al coating on entrance window (optical block) worsens efficiency, difficult integration in vacuum vessel

very low leakage per pixel, pixel to pixel variability, requires long integration time differently from ultra-fast experimental conditions

real experimental conditions: whole charge deposited in a pixel in one single frame, flat-field intensity on the whole sensor

First calibration campaign on the first DEPFET ladder has been carried out

photons

photons

Cfcf=1

ADU

ADU

ADU

ADCFine=1:64

Linear gain calibration and noise



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Non Linear response: qualification with XFEL beam

- Dedicated beamtime at SQS EuXFEL
- XFEL beam impacting on Al target, XRF emission proportional to beam intensity (E=1.486 KeV)
- To scan the NL curve we change beam attenuation (i.e. gas transmission)
 - \mapsto gas monitor as reference for beam intensity
- First part of the response is matched with gain extracted from X-ray spectra to calibrate in energy
- Deposited energy up to few MeV/pixel









Spectral performance and NL response of the ladder @ XFEL



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Conclusions

- FEL facilities push for improvements in detector technologies. DSSC project aims at providing a camera with the desired performances in terms of frame-rate, noise and dynamic range for the soft X-ray spectrum band
- The first miniSDD camera is already available for user experiments, satisfying most of the requirements. Lower noise and much higher dynamic range can be reached by the second camera implementing DEPFET with signal compression
- Calibration of the system is a challenge by itself due to limited ADC resolution and high energy required to scan the whole range up to MeV/pxl/pulse in operating conditions
- The experimental qualification of first DEPFET ladder gave a very successful feedback
 - noise level below 15 el rms, 4 times better than the miniSDD camera and near pnCCD detectors, but at the much higher frame-rate of 4.5 MHz
 - gain/noise accurate calibration from PulXar spectra @ Cu Ka (8 keV), confirmed at SQS @ Al Ka (1.48 keV)
 - intensity scan up to 3 MeV/pixel over the whole ladder led to NL characterization of all pixels
- What's next? Optimization of the calibration procedure for the 1Mpxl DEPFET camera and preparation of the experimental campaign. Assembly of the full DEPFET camera expected by the end of 2022